

**Search Notes**

Application/Control No.

10/564,894

Applicant(s)/Patent under  
Reexamination

MORIYA ET AL.

Examiner

Hai H. Huynh

Art Unit

3747

**SEARCHED**

| Class | Subclass | Date      | Examiner |
|-------|----------|-----------|----------|
| 123   | 299      | 8/23/2006 | HHH      |
| 123   | 300      | 8/23/2006 | HHH      |
| 123   | 305      | 8/23/2006 | HHH      |
| 123   | 406.22   | 8/23/2006 | HHH      |
| 123   | 406.26   | 8/23/2006 | HHH      |
| 123   | 435      | 8/23/2006 | HHH      |
| 123   | 90.15    | 8/23/2006 | HHH      |
| 701   | 103-105  | 8/23/2006 | HHH      |
| 701   | 111      | 8/23/2006 | HHH      |
| 73    | 117.3    | 8/23/2006 | HHH      |
| 73    | 118.1    | 8/23/2006 | HHH      |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|      | DATE      | EXMR |
|------|-----------|------|
| East | 8/23/2006 | HHH  |
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